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D	A NDAI NLIT RAV	AR VIN	ZE Y G			PREPARED BY Kick C. Office CHECKER BY Charles E. Beatro MICROCIRCUIT, LINEAR, DUAL 1 MULTIPLYING CMOS D/A CONVERT MONOLITHIC SILICON					1 544 4	2-B1			RED											
THIS DR FOR USE AND DEPAR AMSC	BY ALI AGENO ITMENT	DEF	PART	HEN'	rs		DRAWING APPROVAL DATE 31 OCTOBER 1989 REVISION LEVEL A						SIZE	CAGE CODE 67268 59				59	962-89671							

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« U.S. GOVERNMENT PRINTING OFFICE: 1987 --- 748-129/60911

1. SCOPE									
1.1 Scope. This drawing describes device with 1.2.1 of MIL-STD-883, "Provisions for mon-JAN devices".	e require the use o	ments f MIL-	for class B mi STD-883 in cor	crocircuit njunction w	s in accordance ith compliant				
1.2 Part number. The complete part number	per shall	be as	shown in the 1	following e	xample:				
5962-89671 01			L 	X 					
1.2.1 <u>Device type</u> . The device type shall	ll identif	y the	circuit funct	ion as foll	ows:				
Device type Generic number	-		function		2422.24				
01 DAC8221A 1.2.2 <u>Case outlines</u> . The case outlines as follows:					; CMOS D/A converter				
Outline letter			Case outlin	<u>e</u>					
Ĺ	D-9 (24 1e	ead, 1.	.280" x .310"	x .200"), d	lual-in-line package				
3 C-4 (28-terminal, .460" x .460" x .100"), square leadless chip carrier package									
1.3 Absolute maximum ratings.									
VDD to AGND									
1.4 Recommended operating conditions.									
Ambient operating temperature (T _A)									
$\underline{1}$ / Derate above 75°C at 6.6 mW/°C.									
STANDARDIZED	SIZE								
MILITARY DRAWING	A		PER 401011 F1 77	L	962-89671				
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444			REVISION LEVEL	- A	SHEET 2				

_			_		
2	APPI	TCARI	F	DOCH	MENTS

2.1 Government specification, standard, and bulletin. Unless otherwise specified, the following specification, standard, and bulletin of the Issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510

- Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883

Test Methods and Procedures for Microelectronics.

BULLETIN

MILITARY

MIL-BUL-103

- List of Standardized Military Drawings (SMD's).

(Copies of the specification, standard, and bulletin required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

3. REQUIREMENTS

- 3.1 <u>Item requirements</u>. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.
- 3.2 <u>Design, construction, and physical dimensions</u>. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.
 - 3.2.1 Terminal connection. The terminal connection shall be as specified on figure 1.
 - 3.2.2 Truth table. The truth table shall be as specified on figure 2.
 - 3.2.3 Functional diagram. The functional diagram shall be as specified on figure 3.
 - 3.2.4 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.
- 3.3 Electrical performance characteristics. Unless otherwise specified, the electrical performance characteristics are as specified in table I and shall apply over the full ambient operating temperature range.
- 3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table I.

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444 SIZE A 5962-89671 REVISION LEVEL A 3

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TABLE I. Electrical performance characteristics. Conditions $-55^{\circ}C \leq T_A \leq +125^{\circ}C$ $V_{OUTA} = V_{OUTB} = 0 \text{ V;}$ $V_{DD} = +5 \text{ V or } +15 \text{ V,}$ $V_{REF} = \pm 10 \text{ V}$ unless otherwise specified Test |Symbol Group A Limits Unit subgroups Min | Max Relative accuracy INL 1, 2, 3 ±1/2| LSB DNL 1, 2, 3 ±1 LSB Differential nonlinearity 1, 2, 3 | ±1 LSB Gain error IGFSE PSRR 1, 2, 3 1±.002| %/% DC power supply rejection ΔGain/ ΔVDD 1/ Output leakage current $^{\rm I}_{\rm OUTA},~^{\rm I}_{\rm OUTB}~\underline{2}/$ i **±** 10 nΑ ILKG 2, 3 ±50 1,2,3 8 | 15 kΩ Input resistance RIN Delta 1, 2, 3 | |±1.0 | % Input resistance match RREF REF 1, 2, 3 | 2.4 ٧ Digital input high ٧_{IH} $V_{DD} = +5 V$ $V_{DD} = +15 V$ 13.5 1, 2, 3 0.8 j v VIL $V_{DD} = +5 V$ Digital input low 1.5 $V_{DD} = +15 V$ $V_{IN} = 0V \text{ or } V_{DD}$ i±1.0 i 1 Input current IIN and VIL or VIH ļμA i±10.0i 2, 3 See footnotes at end of table.

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TABLE I.	Electrical	performance characteristics (Continued				
Test	 Symbol 	Conditions -55°C < TA < +125°C VOUTA = VOUTB = 0 V; VDD = +5 V or +15 V, VREF = ±10 V unless otherwise specified	Group A Isubgroups		its Max 	 Unit 	
Supply current	I _{DD}	Digital inputs V _{IL} or V _{IH}	1, 2, 3	ļ !	2.0	 mA	
		Digital inputs O V or V _{DD}		 	0.1	 	
Input capacitance	CIN	Measuring at D _{BO} - B11 pins, see 4.3.1c	 4 _		10	pF	
		Measuring at WR, CS, DAC A/DAC B pins, see 4.3.1c	 	 	15		
Functional tests		See 4.3.1d	1 7, 8		1 	 	
Chip select to write set-up time 3/	tcs	V _{DD} = +5 V) 9 	130		l ns	
		V _{DD} = +15 V	 	 70	 	 	
	 	V _{DD} = +5 V	10,11	 160 		1 	
	 	V _{DD} = +15 V	_ <u>4/</u> 	70	 	 	
Chip select to write hold time $\underline{3}$ /	t _{CH}	 	9,10,11 <u>4</u> /	 0 	 	l ns	
DAC select to write set-up time 3/	tas	V _{DD} = +5 V	9	120	i i	ns	
	 	V _{DD} = +15 V		70			
	 	V _{DD} = +5 V	10,11	160		ns	
	 	V _{DD} = +15 V	<u>4</u> /	 70	1	` 	
DAC select to write hold time 3/	t _{AH}	 	9,10,11	0		ns	
See footnotes at end of tabl	e.			.•			
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T	ABLE I. Electr	ical performance characteristic	s.			
Test	Symbol	Conditions	Group A	Lim	its	Unit
	 	Conditions $ -55 ^{\circ} C < T_A \leq +125 ^{\circ} C $ $V_{OUTA} = V_{OUTB} = 0 \ V; $ $V_{DD} = +5 \ V \ or \ +15 \ V, $ $V_{REF} = \pm 10 \ V $ unless otherwise specified	subgroups 		 Max 	
Data valid to write set-up time 3/	t _{DS}	V _{DD} = +5 V	9	190	! !	ns I
	 	V _{DD} = +15 V		90	! !	
		V _{DD} = +5 V	10, 11	220	 	
		V _{DD} = +15 V	4/	90	 	
Data valid to write hold time 3/	t _{DH}	V _{DD} = +5 V	9,10,11	0	1	ns
	1	V _{DD} = +15 V		10	 	
Write pulse width $3/$	twR	V _{DD} = +5 V	9	140	 	l ns
		V _{DD} = +15 V		90	! ! <u> </u>	! ! !
		V _{DD} = +5 V	10,11	170	!	
		V _{DD} = +15 V		90	 	

- 1/ Delta $V_{DD} = \pm 5\%$
- 2/ DAC loaded with 000 000 000 000
- 3/ See figure 4.
- 4/ Subgroups 10 and 11, if not tested shall be guaranteed to the limits specified in table I.
- 3.5 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in MIL-BUL-103 (see 6.6 herein).
- 3.6 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-BUL-103 (see 6.6 herein). The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall affirm that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.

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Device type	01					
Case outlines	L	3				
Terminal number	Terminal	symbol				
1	AGND	NC				
2	IOUTA	AGND				
3	R _{FBA}	IOUTA				
4	V _{REFA}	I R _{FBA}				
5	DGND	i v _{refa} i				
6	D _{B11} (MSB)	DGND				
7	D _{B10}	D _{B11} (MSB)				
8	D_{B9}	NC				
9	D _{B8}	D _{B10}				
10	D _{B7}	D _{B9}				
11	D _{B6}	D ₈₈				
12	D _{B5}	D _{B7}				
13	D _{B4}	D _{B6}				
14	D_{B3}	D _{B5}				
15	D _{B2}	NC .				
16	D _{B1}	D _{B4}				
17	D _{BO} (LSB)	D _{B3}				
18	DACA/DACB	l D _{B2} I				
19	टड	D _{B1}				
20	WR	D _{BO} (LSB)				
21	v _{DD}	DACA/DACB				
22	V _{REFB}	NC :				
23	R _{FBB}	टड				
24	IOUTB	WR }				
25		V _{DD}				
26		VREFB				
27		R _{FBB}				
28		I _{OUTB}				

Figure 1. Terminal connections.

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DAC A/ DAC B	CS	WR	DAC A	DAC B
L H X X	L H X	L X H	WRITE HOLD HOLD HOLD	HOLD WRITE HOLD HOLD

L = Low state H = High state X = Don't care

FIGURE 2. Truth table.

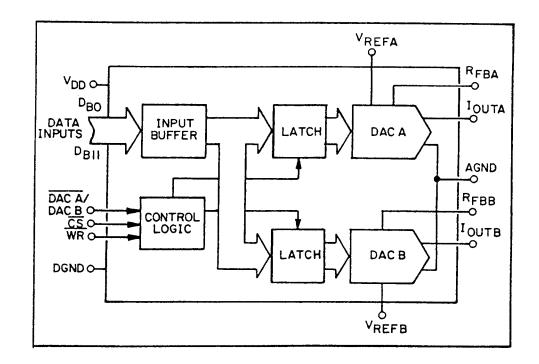
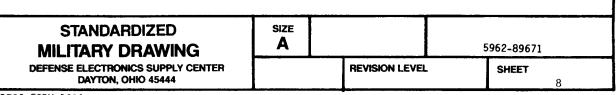
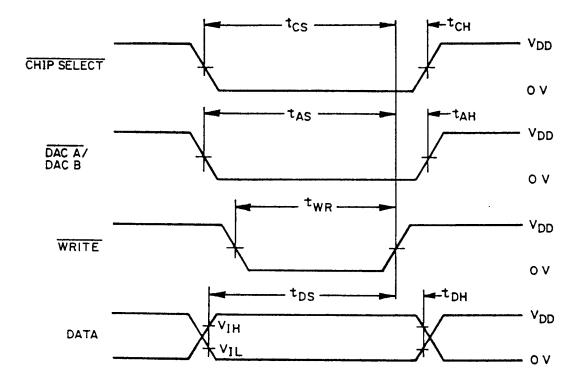


FIGURE 3. Functional diagram.







NOTES:

- 1. All input signal rise and fall times measured from 10 percent to 90 percent of V_{DD} . V_{DD} = +5 V, t_r = t_f = 20 ns; V_{DD} = +15 V, t_r = t_f = 40 ns.
- 2. Timing measurement reference level is $\frac{v_{IH} + v_{II}}{2}$

FIGURE 4. Timing diagram.

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- 3.7 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.
- 3.8 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).
- 3.9 Verification and review. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.
 - 4. QUALITY ASSURANCE PROVISIONS
- 4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).
- 4.2 <u>Screening</u>. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:
 - a. Burn-in test, method 1015 of MIL-STD-883.
 - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.6 herein).
 - (2) $T_A = +125^{\circ}C$, minimum.
 - b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.
- 4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.
 - 4.3.1 Group A inspection.
 - a. Tests shall be as specified in table II herein.
 - b. Subgroups 5 and 6 in table I, method 5005 of MIL-STD-883 shall be omitted.
 - c. Subgroup 4 (C_{IN} measurement) shall be measured only for the initial test and after process or design changes which may affect input capacitance.
 - d. Subgroup 7 and 8 shall include verification of the truth table.

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TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (per method 5005, table I)
Interim electrical parameters (method 5004)	1
Final electrical test parameters (method 5004)	1*, 2, 3, 7, 8
Group A test requirements (method 5005)	1, 2, 3, 4, 7, 8, 9, 10**, 11**
 Group C and D end-point electrical parameters (method 5005)	1

* PDA applies to subgroup 1.

** Subgroups 10 and 11, if not tested, shall be guaranteed to the limits specified in table I.

4.3.2 Groups C and D inspections.

- a. End-point electrical parameters shall be as specified in table II herein.
- b. Steady-state life test conditions, method 1005 of MIL-STD-883.
 - Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.6 herein).
 - (2) $T_A = +125^{\circ}C$, minimum.
 - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.
- 5. PACKAGING
- 5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.
 - 6. NOTES
- 6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.
- 6.2 <u>Replaceability</u>. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

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- 6.3 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished in accordance with MIL-STD-481 using DD Form 1693, Engineering Change Proposal (Short Form).
- 6.4 Record of users. Military and industrial users shall inform Defense Electronics Supply Center when a system application requires configuration control and the applicable SMD. DESC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronics devices (FSC 5962) should contact DESC-ECS, telephone (513) 296-6022.
- 6.5 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone (513) 296-5375.
- 6.6 Approved source of supply. An approved source of supply is listed in MIL-BUL-103. Additional sources will be added to MIL-BUL-103 as they become available. The vendor listed in MIL-BUL-103 has agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DESC-ECS. The approved source of supply listed below is for information purposes only and is current only to the date of the last action of this document.

 Military drawing part number 	Vendor CAGE number	Yendor similar part number 1/	 Replacement military specification part number
 5962-8967101LX 	06 665	DAC-8221AW	
5962-89671013X	06665	DAC-8221ATC	

1/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number

06665

Vendor name and address

Precision Monolithics, Incorporated 1500 Space Park Drive P.O. Box 58020 Santa Clara, CA 95050-8020

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